

Search Notes

Application/Control No.

10/820,144

Examiner

Shin-Lin Chen

Applicant(s)/Patent under
Reexamination

CHANG ET AL.

Art Unit

1632

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated.	12/12/2007	<i>SLC</i>